

*attachment to PTOL - 413  
(do NOT detach)*

NAKANO et al., SN 10/075,244  
19 October 2005 Amendment  
Reply to 19 July 2005 Office Action

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IN THE CLAIMS:

*Proposal - 6/12/06*

1. (Currently Amended) A method for processing a specimen using a plasma, comprising:

generating a plasma in a processing chamber in which the specimen is disposed; and

5 processing the specimen with the plasma generated in the processing chamber, wherein

the processing of the specimen comprises:  
an irradiation operation for projecting and scanning a light beam into the processing chamber through an observation window of the processing chamber;  
10 a detection operation for detecting a light of the projected light beam which is reflected from an inside wall of the processing chamber, the light being detected by separating a light component from light emanated from the plasma and light reflected from the inside wall by use of a spectroscope; and

15 a signal processing operation for obtaining information on a state of contamination of the inside wall of the processing chamber, by processing a signal obtained at the detection operation by referring to a database storing predetermined relationships between a signal obtained from said detection of light from said inside wall and a state of contamination of said inside wall.

*TO DERIVE A STATE OF CONTAMINATION  
CORRESPONDING TO THE WALL-REFLECTED LIGHT  
SIGNAL, FROM THE ELECTRONIC DATABASE.*

2. (Previously Presented) A method for processing a specimen using a plasma according to Claim 1, comprising